



**ALPHA & OMEGA**  
SEMICONDUCTOR

# AOT2502L/AOB2502L

150V N-Channel MOSFET

## General Description

- Trench Power MV MOSFET technology
- Low  $R_{DS(ON)}$
- Low Gate Charge
- Optimized for fast-switching applications

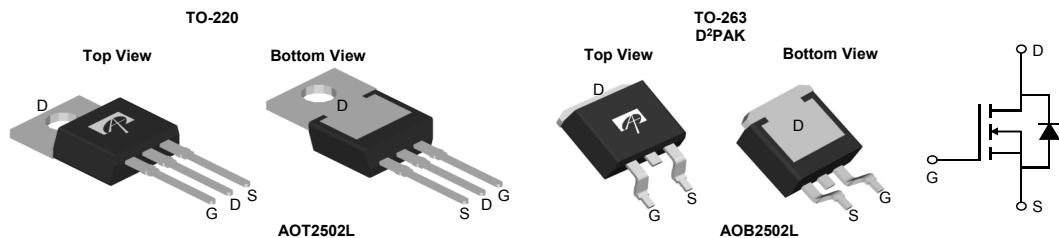
## Applications

- Synchronous Rectification in DC/DC and AC/DC Converters
- Industrial and Motor Drive applications

## Product Summary

$V_{DS}$	150V
$I_D$ (at $V_{GS}=10V$ )	106A
$R_{DS(ON)}$ (at $V_{GS}=10V$ )	< 11mΩ (10.7mΩ*)

100% UIS Tested  
100%  $R_g$  Tested



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AOT2502L	TO-220	Tube	1000
AOB2502L	TO-263	Tape & Reel	800

## Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	150	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$I_D$	106	A
$T_c=100^\circ C$		67	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	250	
Continuous Drain Current	$I_{DSM}$	18.5	A
$T_A=70^\circ C$		14.5	
Avalanche Current <sup>C</sup>	$I_{AS}$	40	A
Avalanche energy $L=0.3mH$ <sup>C</sup>	$E_{AS}$	240	mJ
$V_{DS}$ Spike	10μs	$V_{SPIKE}$	V
Power Dissipation <sup>B</sup>	$P_D$	277	W
$T_c=100^\circ C$		111	
Power Dissipation <sup>A</sup>	$P_{DSM}$	8.3	W
$T_A=70^\circ C$		5.3	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

## Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$t \leq 10s$	$R_{\theta JA}$	12	°C/W
Maximum Junction-to-Ambient <sup>A,D</sup>	Steady-State		50	°C/W
Maximum Junction-to-Case	Steady-State	$R_{\theta JC}$	0.35	°C/W

\* Surface mount package TO-263

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}$ , $V_{GS}=0\text{V}$	150			V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=150\text{V}$ , $V_{GS}=0\text{V}$		1		$\mu\text{A}$
			$T_J=55^\circ\text{C}$		5	
$I_{GSS}$	Gate-Body leakage current	$V_{DS}=0\text{V}$ , $V_{GS}=\pm 20\text{V}$			$\pm 100$	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_D=250\mu\text{A}$	3.5	4.3	5.1	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}$ , $I_D=20\text{A}$		9.2	11	$\text{m}\Omega$
		$\text{TO-220}$	$T_J=125^\circ\text{C}$		17.8	
		$V_{GS}=10\text{V}$ , $I_D=20\text{A}$ $\text{TO-263}$			8.9	
$g_{FS}$	Forward Transconductance	$V_{DS}=5\text{V}$ , $I_D=20\text{A}$		50		S
$V_{SD}$	Diode Forward Voltage	$I_S=1\text{A}$ , $V_{GS}=0\text{V}$		0.7	1	V
$I_S$	Maximum Body-Diode Continuous Current				106	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}$ , $V_{DS}=75\text{V}$ , $f=1\text{MHz}$		3010		pF
$C_{oss}$	Output Capacitance			345		pF
$C_{rss}$	Reverse Transfer Capacitance			14		pF
$R_g$	Gate resistance	$f=1\text{MHz}$	1	2	3	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}$ , $V_{DS}=75\text{V}$ , $I_D=20\text{A}$		43	60	nC
$Q_{gs}$	Gate Source Charge			18		nC
$Q_{gd}$	Gate Drain Charge			10		nC
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{GS}=10\text{V}$ , $V_{DS}=75\text{V}$ , $R_L=3.75\Omega$ , $R_{\text{GEN}}=3\Omega$		19		ns
$t_r$	Turn-On Rise Time			24		ns
$t_{D(\text{off})}$	Turn-Off DelayTime			30		ns
$t_f$	Turn-Off Fall Time			8.5		ns
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F=20\text{A}$ , $dI/dt=500\text{A}/\mu\text{s}$		75		ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F=20\text{A}$ , $dI/dt=500\text{A}/\mu\text{s}$		880		nC

A. The value of  $R_{\text{QJA}}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The Power dissipation  $P_{\text{DSM}}$  is based on  $R_{\text{QJA}} \approx 10\text{s}$  and the maximum allowed junction temperature of  $150^\circ\text{C}$ . The value in any given application depends on the user's specific board design, and the maximum temperature of  $150^\circ\text{C}$  may be used if the PCB allows it.

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=150^\circ\text{C}$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{C}$ .

D. The  $R_{\text{QJA}}$  is the sum of the thermal impedance from junction to case  $R_{\text{QJC}}$  and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=150^\circ\text{C}$ . The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ .

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

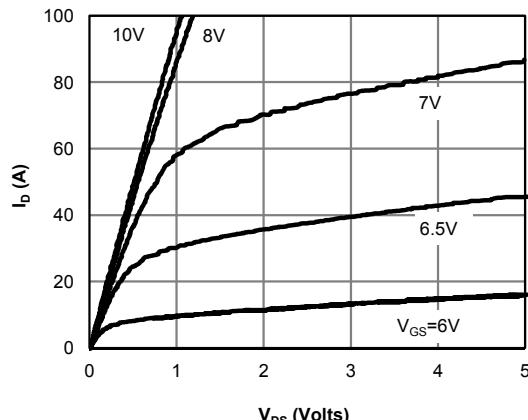


Figure 1: On-Region Characteristics (Note E)

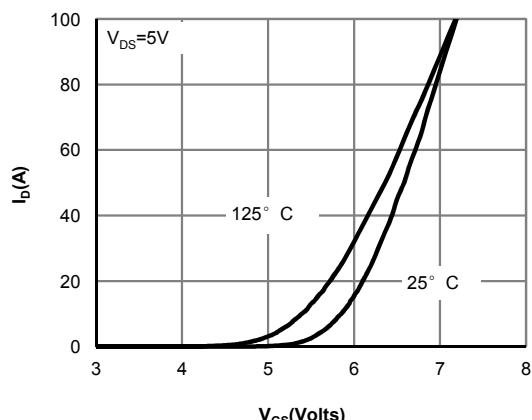


Figure 2: Transfer Characteristics (Note E)

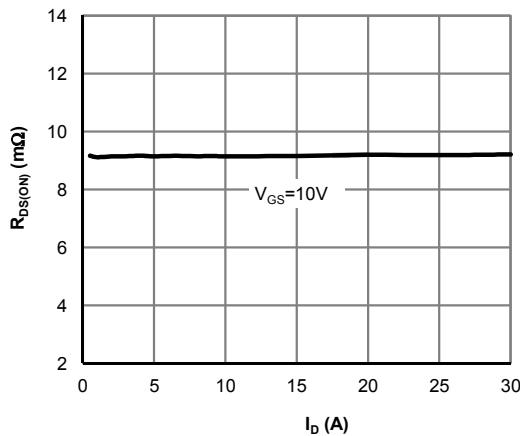


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

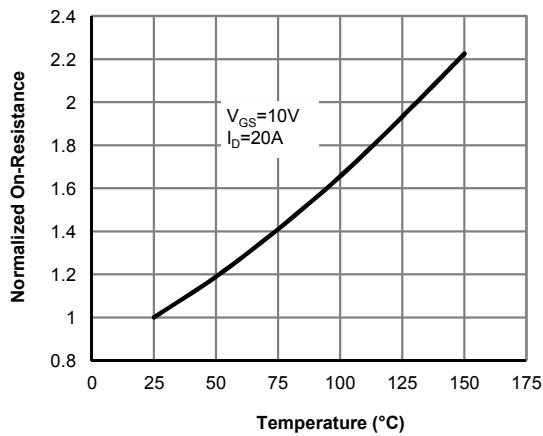


Figure 4: On-Resistance vs. Junction Temperature (Note E)

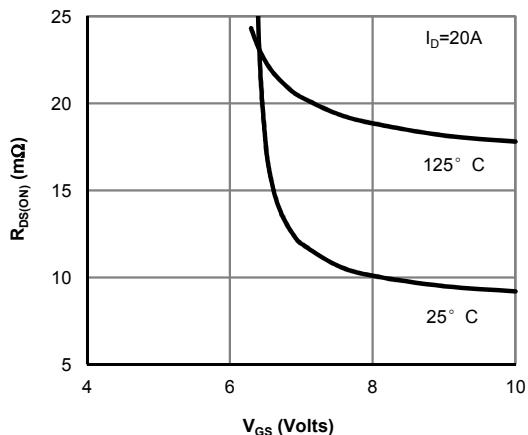


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

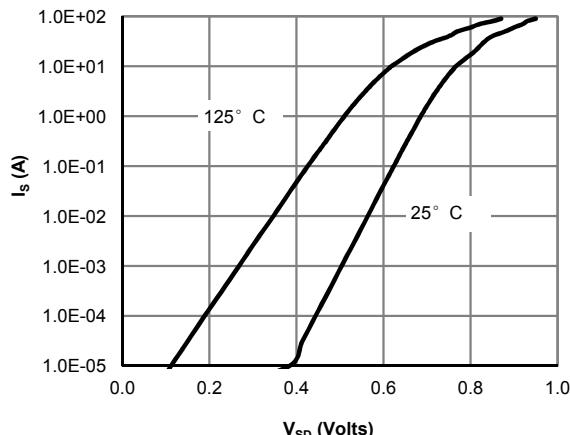


Figure 6: Body-Diode Characteristics (Note E)



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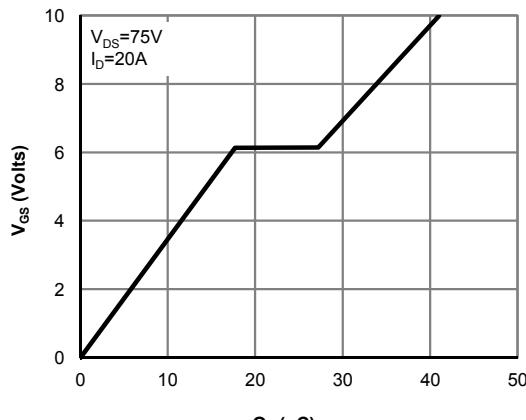


Figure 7: Gate-Charge Characteristics

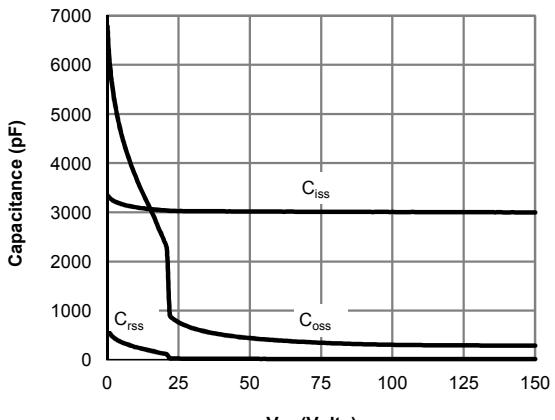


Figure 8: Capacitance Characteristics

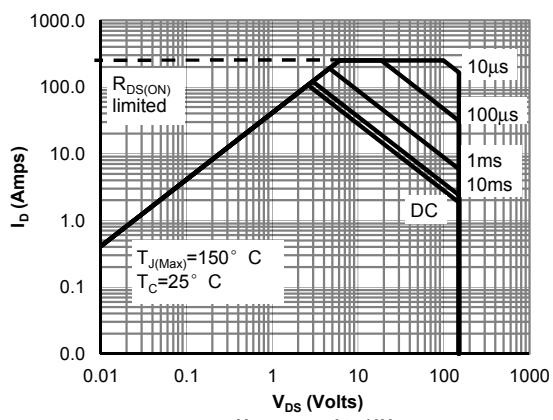


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

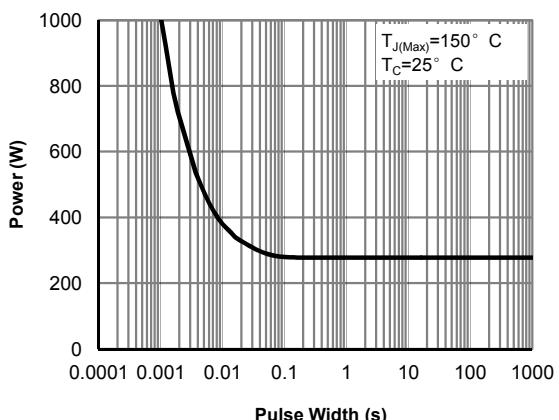


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

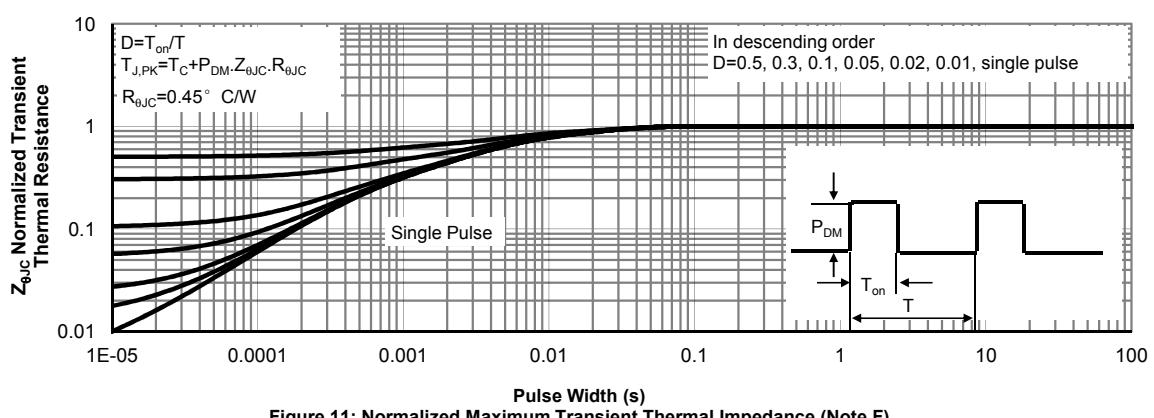


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)



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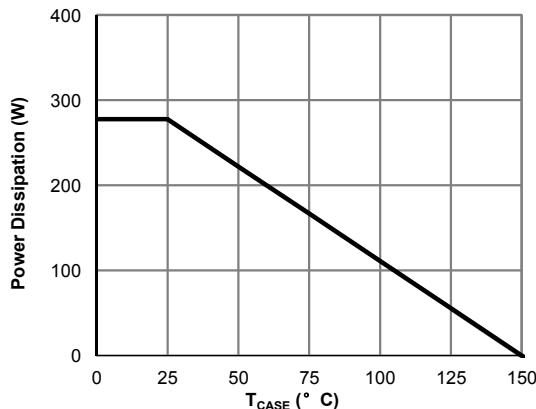


Figure 12: Power De-rating (Note F)

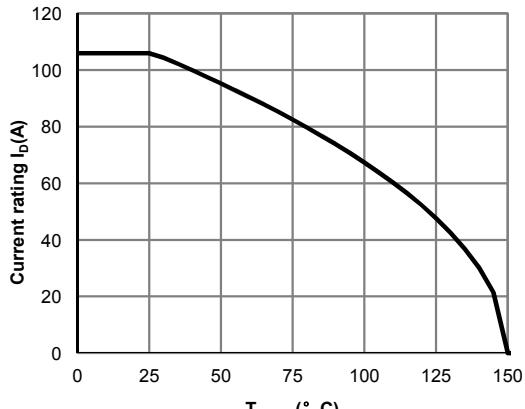


Figure 13: Current De-rating (Note F)

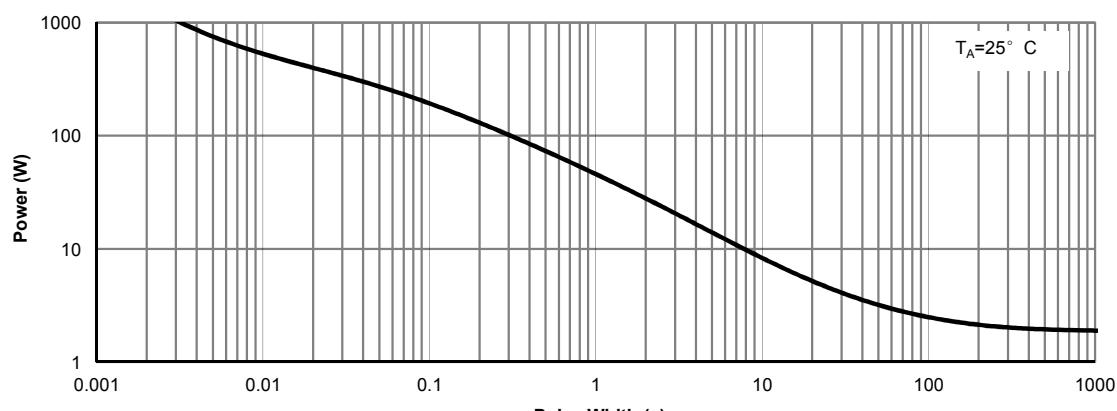


Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note H)

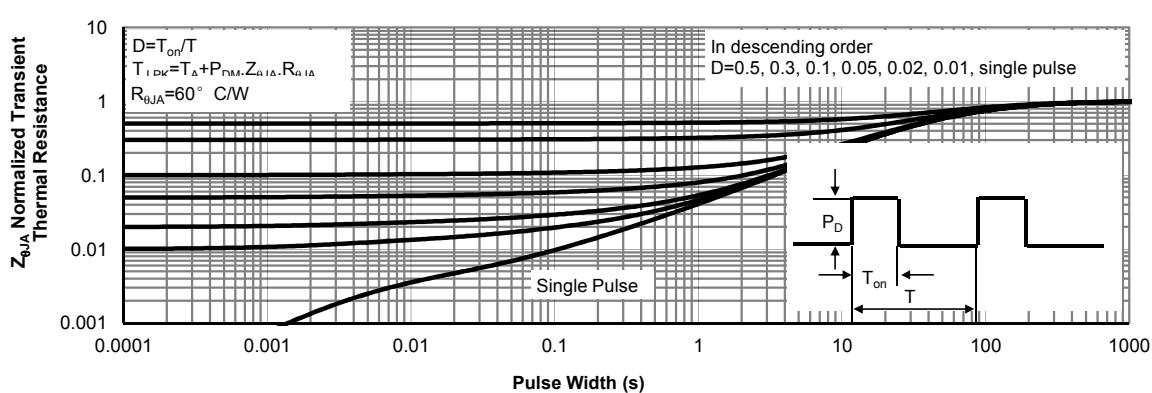
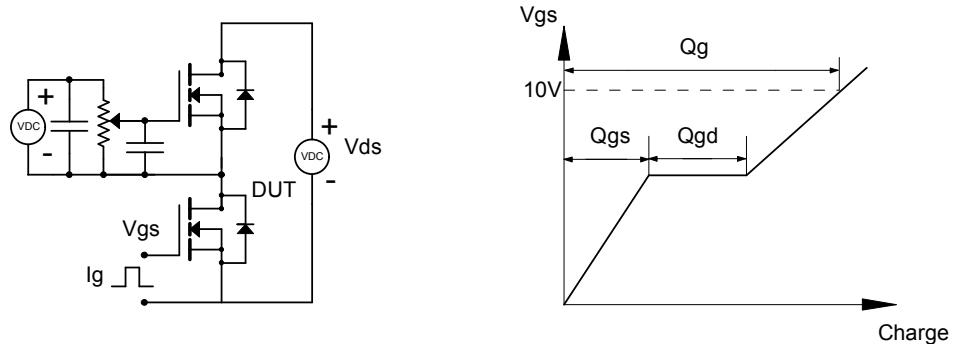


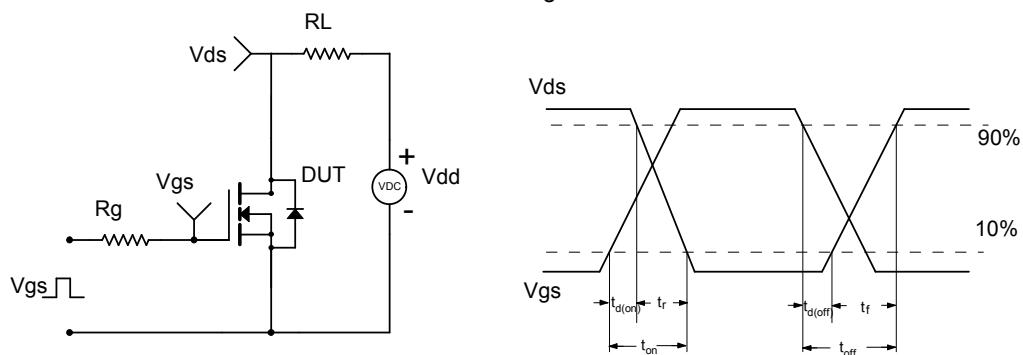
Figure 15: Normalized Maximum Transient Thermal Impedance (Note H)



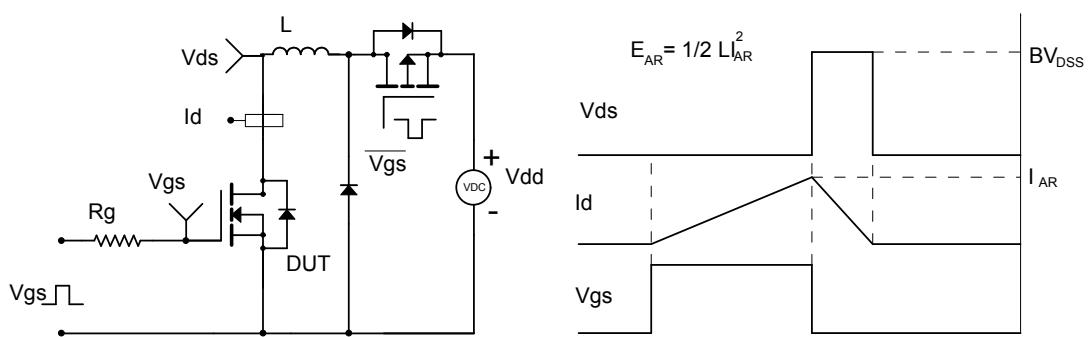
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

